

Notice of References Cited	Application/Control No. 10/560,723		Applicant(s)/Patent Under Reexamination EINSTEIN ET AL.	
	Examiner SEAN E. AEDER		Art Unit 1642	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,812,339 B1	11-2004	Venter et al.	536/24.31
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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*	N	WO 01/60860 A2	08-2001		Schlegel et al	
	O					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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